

Search Notes

Application/Control No.

09/764,778

Examiner

JAGDISH PATEL

Applicant(s)/Patent under
Reexamination

SIREAU, JEAN-YVES

Art Unit

3624

SEARCHED

Class	Subclass	Date	Examiner
705	37 37	3/30/2006 2/12/07	<i>gnd</i> <i>gnd</i>
463	26	2/12/07	<i>gnd</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
705	37	2/12/07	<i>gnd</i>
463	26	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (Patent Databases, US & Foreign)	3/30/2006 10/10/2006	<i>gnd</i>
Dialog NPL (Business Databases)	3/30/2006 10/10/2006	<i>gnd</i>